

<b>Notice of References Cited</b>	Application/Control No. 10/533,029		Applicant(s)/Patent Under Reexamination BONNEFOUS, ODILE	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,067,236 A	01-1978		73/861.25
*	B	US-4,103,679 A	08-1978	Aronson, Harmon J.	600/456
*	C	US-4,265,126 A	05-1981	Papadofrangakis et al.	73/861.25
*	D	US-4,612,937 A	09-1986	Miller, Lawrence R.	600/441
*	E	US-4,790,322 A	12-1988	Iinuma, Kazuhiro	600/456
*	F	US-5,197,477 A	03-1993	Peterson et al.	600/454
*	G	US-5,262,785 A	11-1993	Silverstein et al.	342/162
*	H	US-5,257,629 A	11-1993	Kitney et al.	600/463
*	I	US-5,322,067 A	06-1994	Prater et al.	600/443
*	J	US-5,357,964 A	10-1994	Spivey et al.	600/455
*	K	US-5,386,830 A	02-1995	Powers et al.	600/455
*	L	US-5,443,071 A	08-1995	Banjanin et al.	600/455
*	M	US-5,454,371 A	10-1995	Fenster et al.	600/443

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

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**Notice of References Cited**

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,474,073 A	12-1995	Schwartz et al.	600/456
*	B	US-5,471,990 A	12-1995	Thirsk, Graham	600/455
*	C	US-5,485,842 A	01-1996	Quistgaard, Jens U.	600/443
*	D	US-5,570,691 A	11-1996	Wright et al.	600/447
*	E	US-5,623,930 A	04-1997	Wright et al.	600/456
*	F	US-5,675,554 A	10-1997	Cole et al.	367/138
*	G	US-5,678,554 A	10-1997	Hossack et al.	600/459
*	H	US-5,720,291 A	02-1998	Schwartz, Gary Allen	600/456
*	I	US-5,724,976 A	03-1998	Mine et al.	600/459
*	J	US-5,876,345 A	03-1999	Eaton et al.	600/466
*	K	US-5,928,151 A	07-1999	Hossack et al.	600/443
*	L	US-5,980,458 A	11-1999	Clark, David W.	600/437
*	M	US-6,171,248 B1	01-2001	Hossack et al.	600/459

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,213,947 B1	04-2001	Phillips, Patrick	600/443
*	B	US-6,241,675 B1	06-2001	Smith et al.	600/443
*	C	US-6,283,918 B1	09-2001	Kanda et al.	600/441
*	D	US-6,322,511 B1	11-2001	Guracar et al.	600/453
*	E	US-6,374,674 B1	04-2002	Mine, Yoshitaka	73/606
*	F	US-6,390,980 B1	05-2002	Peterson et al.	600/443
*	G	US-6,383,139 B1	05-2002	Hwang et al.	600/441
*	H	US-6,425,868 B1	07-2002	Tamura, Tadashi	600/454
*	I	US-6,458,082 B1	10-2002	Jackson et al.	600/441
*	J	US-6,530,885 B1	03-2003	Entrekin et al.	600/437
*	K	US-6,572,548 B2	06-2003	Cerofolini, Marino	600/443
*	L	US-2003/0158477 A1	08-2003	Panescu, Dorin	600/424
*	M	US-6,682,483 B1	01-2004	Abend et al.	600/437

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,685,641 B2	02-2004	Liu, D-L Donald	600/443
*	B	US-6,780,155 B2	08-2004	Li, Xiang-Ning	600/454
*	C	US-2005/0053305 A1	03-2005	Li et al.	382/260
*	D	US-6,918,876 B1	07-2005	Kamiyama, Naohisa	600/447
*	E	US-7,171,255 B2	01-2007	Holupka et al.	600/427
*	F	US-7,201,715 B2	04-2007	Burdette et al.	600/3
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lockwood, G.R., et al., "Real-Time 3-D Ultrasound Imaging Using Sparse Synthetic Aperture Beamforming", IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control, Jul. 1998, vol. 45, No. 4, 980-988.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.